Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/085,063	ARAI ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

	SEARCHED				
Class	Subclass	Date	Examiner		
438	691	6/30/2005	3+		
438	692	6/30/2005	灯		
438	693	6/30/2005	BT		
438	697	6/30/2005	町		
438	699	6/30/2005	135		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
438	691	6/30/2005	br	
438	692	6/30/2005	BT	
· 438	693	6/30/2005	By	
438/697 438/699		6/30/2005	BT	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update search using USPAT, US- PGPUB, EPO, JPO, DERWENT database	6/30/2005	BY		
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